

Appl. No. 10/707,560
Amdt. dated September 16, 2005
Reply to Office action of June 22, 2005

Amendments to the Claims:

Listing of Claims:

Claim 1 (currently amended) A method of repairing electrode pattern
5 defects comprising:

performing an inspection process for determine electrode pattern defects; and

10 performing a first one-step repairing process with a conductive paste for repairing the electrode pattern ~~electrode~~ defects.

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Claim 2 (original) The method of claim 1, wherein the electrode pattern is a sustain electrode pattern of a plasma display panel (PDP).

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Claim 3 (original) The method of claim 2, wherein the sustain electrode is composed of a transparent conductive material or a metal conductive material.

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Claim 4 (original) The method of claim 1, wherein the electrode pattern defects comprise a pit part such as a hole, an incomplete connection, or a broken connection.

25 Claim 5 (currently amended) The method of claim 4, wherein the first one-step repairing process is performed via either partially or completely filling the pit part with [[a]] the conductive paste.

Claim 6 (original) The method of claim 5, wherein the conductive paste is selected from a group consisting of silver paste, ITO paste, IZO

Appl. No. 10/707,560
Amdt. dated September 16, 2005
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paste, gold paste, and silver glue.

Claim 7 (original) The method of claim 1, wherein the electrode pattern defects comprise salient parts.

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Claim 8 (original) The method of claim 7, wherein the method further comprises performing a second repairing process, the second repairing process removing the salient part by means of a laser beam.

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Claim 9 (original) The method of claim 1, wherein the inspection process comprises an optical inspection process or an electrical inspection process.

15 Claim 10 (currently amended) A method of repairing electrode pattern defects of a plasma display panel (PDP) comprising:

performing an inspection process to determine a first pit defect and a second salient defect of the plasma display panel;

20 performing a first one-step repairing process for filling the first pit defect; and

performing a second repairing process for removing the second salient defect.

25 Claim 11 (original) The method of claim 10, wherein the electrode pattern is composed of a transparent conductive material or a metal conductive material.

Claim 12 (currently amended) The method of claim 10, wherein the first

Appl. No. 10/707,560
Amtd. dated September 16, 2005
Reply to Office action of June 22, 2005

~~defect is a pit part of the electrode pattern such as pit defect comprises a hole, an incomplete connection, or a broken connection.~~

5 Claim 13 (currently amended) The method of claim [[12]] 10, wherein the first one-step repairing process fills the pit [part of the electrode pattern] defect with a conductive paste.

10 Claim 14 (original) The method of claim 13, wherein the conductive paste is selected from a group consisting of silver paste, ITO paste, IZO paste, gold paste, and silver glue.

15 Claim 15 (currently amended) The method of claim 13, wherein the pit [[part]] defect is completely filled up in the first one-step repairing process.

20 Claim 16 (currently amended) The method of claim 13, wherein the pit [[part]] defect is partially filled up in the first one-step repairing process.

Claim 17 (cancelled)

25 Claim 18 (currently amended) The method of claim [[17]] 10, wherein the second repairing process removes the salient [[part]] defect by means of a laser beam.

Claim 19 (original) The method of claim 10, wherein the inspection process

Appl. No. 10/707,560
Amdt. dated September 16, 2005
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comprises an optical inspection process or an electrical inspection process, and the electrode pattern comprises a sustain electrode pattern, a bus electrode pattern, or an address electrode pattern.

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